

UNISONIC TECHNOLOGIES CO., LTD

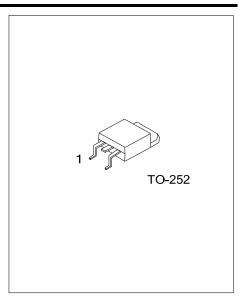
F1N60Q-TD Preliminary

Power MOSFET

1.0A, 600V N-CHANNEL POWER MOSFET

■ DESCRIPTION

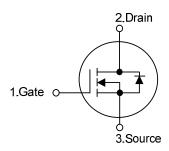
The UTC **F1N60Q-TD** is a N-Channel enhancement mode silicon gate power MOSFET with Fast Body Diode, is designed high voltage, high speed power switching applications such, is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient AC to DC converters and bridge circuits.



■ FEATURES

- * $R_{DS(ON)} \le 8.6 \Omega$ @ V_{GS} =10V, I_D =0.5A
- * Fast body diode MOSFET technology
- * Fast switching capability
- * Avalanche energy tested
- * Improved dv/dt capability, high ruggedness

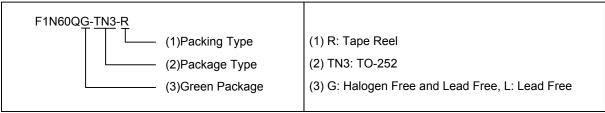
■ SYMBOL



■ ORDERING INFORMATION

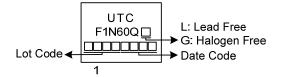
Ordering Number		Daalaaaa	Pin Assignment			Daaldaa	
Lead Free	Halogen Free	Package	1	2	3	Packing	
F1N60QL-TN3-R	F1N60QG-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



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■ MARKING



■ **ABSOLUTE MAXIMUM RATINGS** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	600	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Drain Current	Continuous	I_{D}	1	Α	
	Pulsed (Note 2)	I_{DM}	2	Α	
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	16	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.25	V/ns	
Power Dissipation		P _D	29	W	
Junction Temperature		TJ	+150	°C	
Storage Temperature		T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=1.0mH, I_{AS} =1.8A, V_{DD} =50V, R_{G} =25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 4. $I_{SD} \le 2.4A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	110	°C/W	
Junction to Case	θ_{Jc}	4.31	°C/W	

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

Preliminary

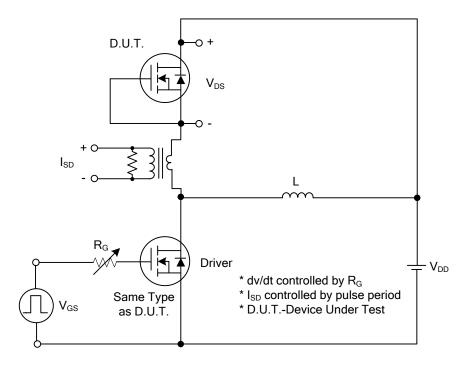
■ **ELECTRICAL CHARACTERISTICS** (T_J=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250μA	600			V	
Drain-Source Leakage Current	I _{DSS}	V _{DS} =600V,V _{GS} =0V			10	μΑ	
Cata Cauras I sakara Current		V _{GS} =+30V			100	nA	
Gate-Source Leakage Current	I _{GSS}	V _{GS} =-30V			-100	nA	
ON CHARACTERISTICS							
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$	2.0		4.0	V	
Drain to Source On-state Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =0.5A			8.6	Ω	
DYNAMIC PARAMETERS							
Input Capacitance	C _{ISS}			150		pF	
Output Capacitance	Coss	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		21		pF	
Reverse Transfer Capacitance	C _{RSS}	<u>] </u>		2.6		pF	
SWITCHING PARAMETERS							
Total Gate Charge (Note 1)	Q_G	\/ -480\/ \/ -10\/ -1A		9		nC	
Gate Source Charge	Q_GS	V _{DS} =480V, V _{GS} =10V, I _D =1A, I _G =1mA (Note 1, 2)		4		nC	
Gate Drain Charge	Q_GD	IG-IIIIA (Note 1, 2)		1.5		nC	
Turn-ON Delay Time (Note 1)	t _{D(ON)}			4		ns	
Turn-ON Rise Time	t _R	V_{DD} =300V, V_{GS} =10V, I_{D} =1A,		16		ns	
Turn-OFF Delay Time	t _{D(OFF)}	R _G =25Ω (Note 1, 2)		12		ns	
Turn-OFF Fall-Time	t _F			38		ns	
SOURCE- DRAIN DIODE RATINGS AND CHA	ARACTERIS	STICS					
Maximum Continuous Drain-Source Diode	,				1	Α	
Forward Current	I _S				'	А	
Maximum Pulsed Drain-Source Diode	I _{SM}				2	Α	
Forward Current	ISM					^	
Drain-Source Diode Forward Voltage (Note 1)	V_{SD}	I _S =1A, V _{GS} =0V			1.4	V	
Reverse Recovery Time (Note 1)	t _{rr}	 s=1A,V _{GS} =0V, dl/dt=100A/μs		70		ns	
Reverse Recovery Charge	Q _{rr}	is= iA, v _{GS} =υν, αι/αι= ισυΑ/μS		170		nC	

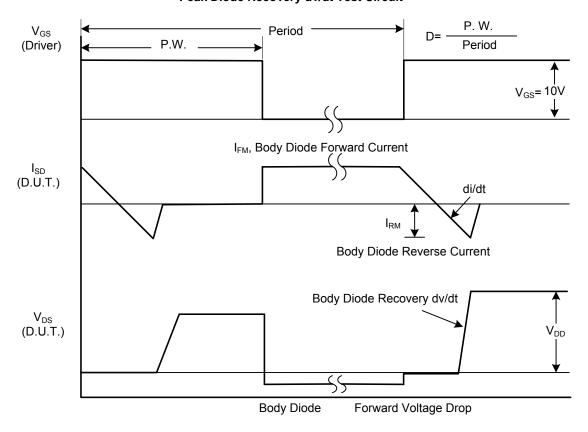
Notes: 1. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2%.

^{2.} Essentially independent of operating ambient temperature.

■ TEST CIRCUITS AND WAVEFORMS

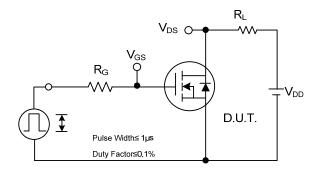


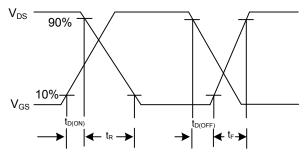
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

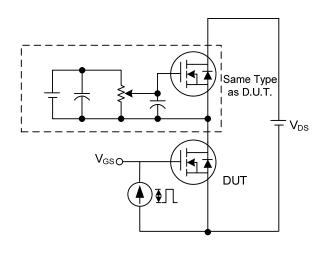
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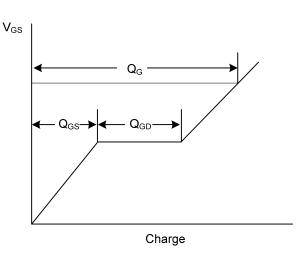




Switching Test Circuit

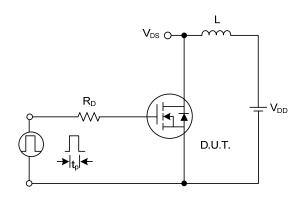
Switching Waveforms

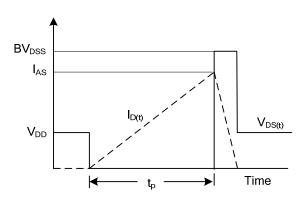




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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